

Annex -C

SAR Measurement Reports

Measurement Report for IC-F4400DT, , , CW, Channel 0 (450.000 MHz) Device Under Test

Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT, ICOM	50.0 x 10.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,	CW, 0--		450.000, 0	10.65	0.866	44.3

Hardware Setup

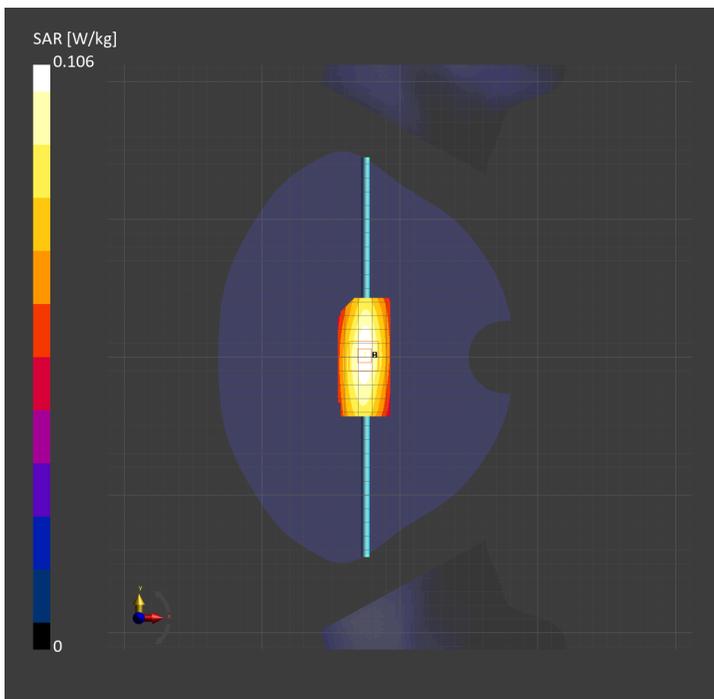
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-29, 15:38	2025-05-29, 15:43
psSAR1g [W/Kg]	0.101	0.102
psSAR10g [W/Kg]	0.070	0.068
Power Drift [dB]	0.01	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.1
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT , , , CW, Channel 0 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT , ICOM	50.0 x 10.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid		CW, 0--		450.000, 0	10.65	0.815	43.1

Hardware Setup

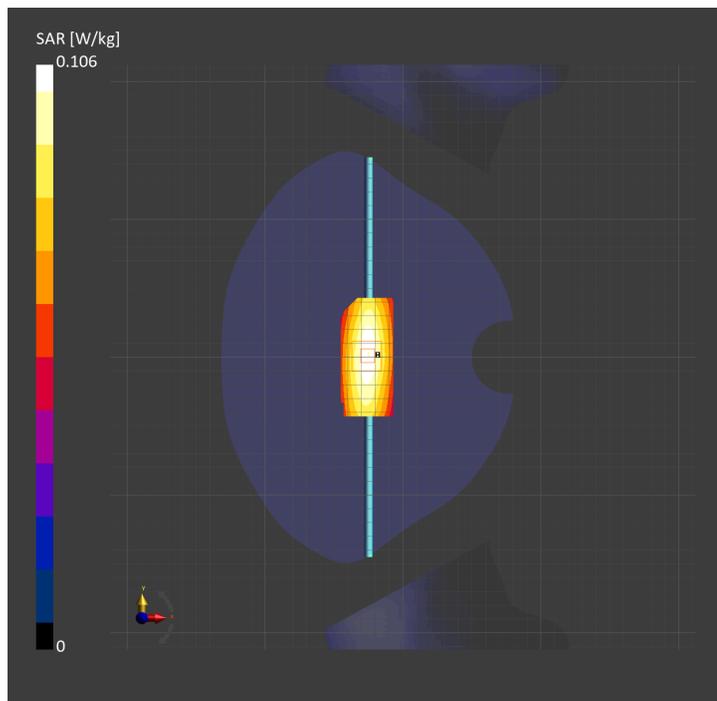
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-04	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04, 11:10	2025-06-04, 11:15
psSAR1g [W/Kg]	0.098	0.099
psSAR10g [W/Kg]	0.068	0.066
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		> 15.0



Pre Scan

Battery – Body

Body SAR					
Battery		Output Power (W)	Freq	Body SAR 1g(W/Kg)	Body SAR 10g(W/Kg)
BP-283	2010mAh	5.3	470	6.000	4.380
BP-284	3210mAh	5.3	471	5.800	4.270
BP-303	3350mAh	5.3	472	0.743	0.547
BP-305	5xAA	5.3	473	0.206	0.075

Measurement Report for IC-F4400DT – S82US, BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

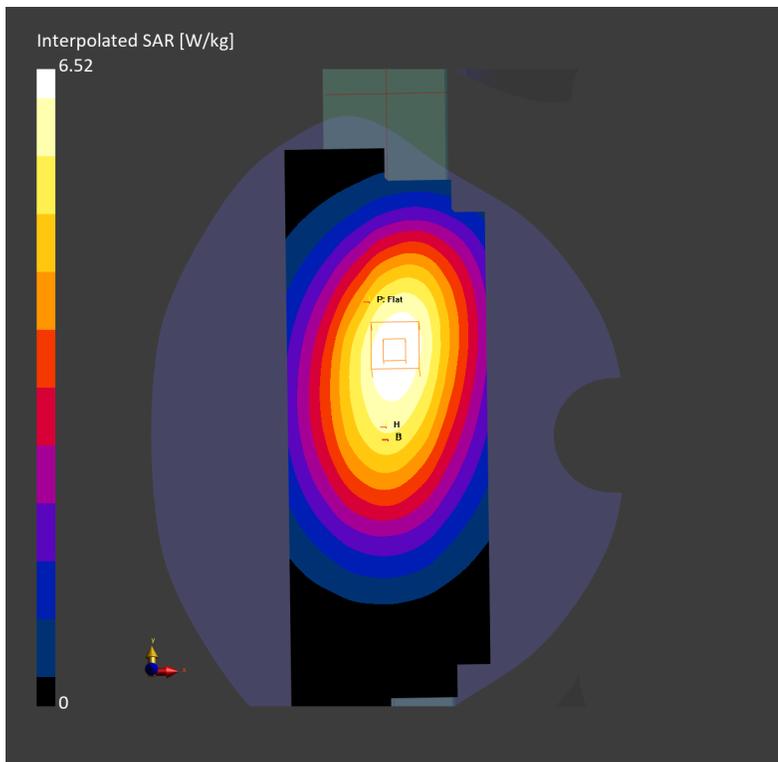
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 09:55	2025-06-02, 10:01
psSAR1g [W/Kg]	5.82	6.00
psSAR10g [W/Kg]	4.22	4.38
Power Drift [dB]	0.04	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.3
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – BP284 S82US, BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – BP284 S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

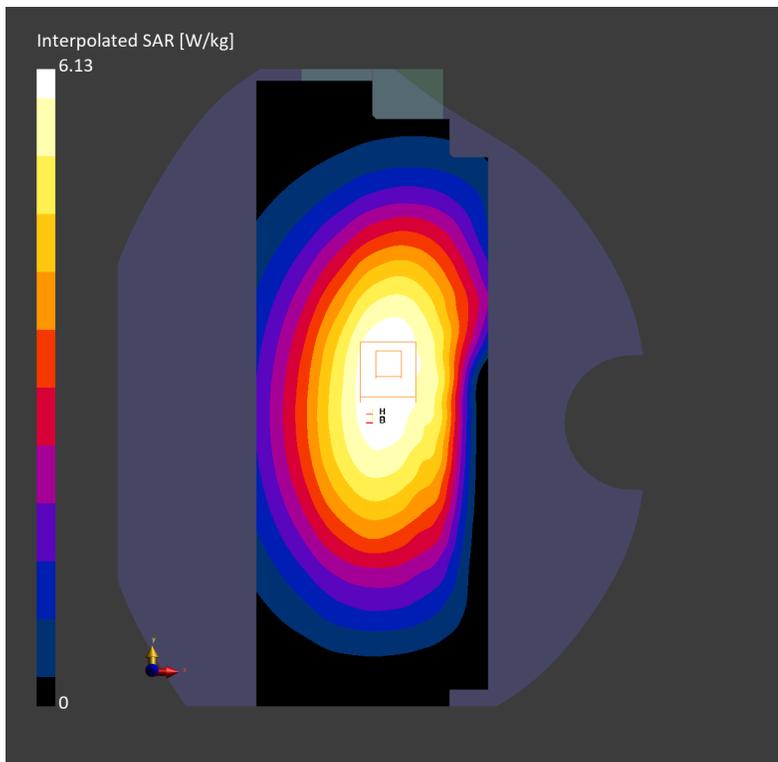
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30, 10:52	2025-05-30, 10:58
psSAR1g [W/Kg]	5.48	5.80
psSAR10g [W/Kg]	4.01	4.27
Power Drift [dB]	-0.49	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.7
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – BP303 S82US, BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – BP303 S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

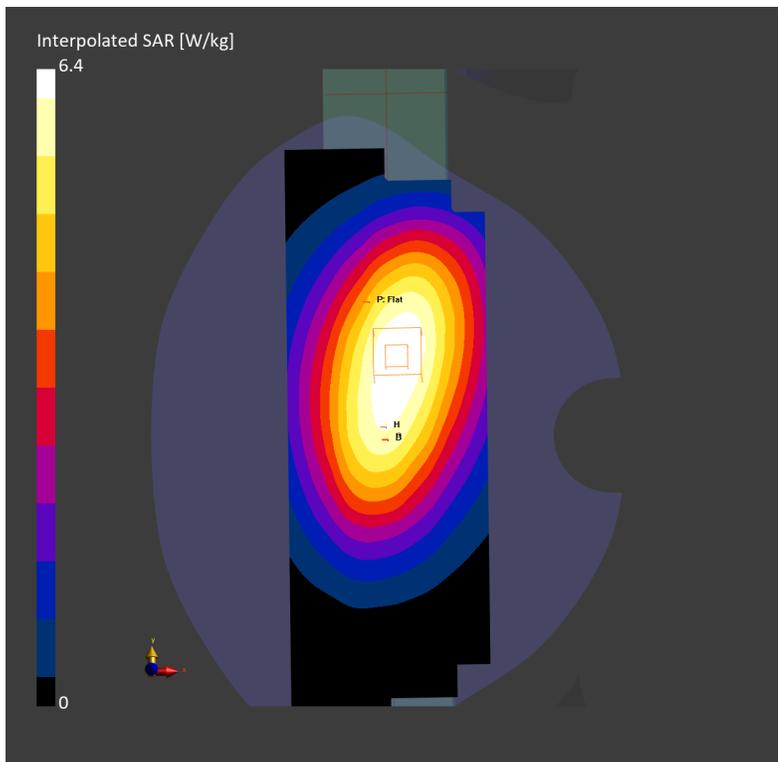
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30, 13:43	2025-05-30, 13:50
psSAR1g [W/Kg]	0.739	0.743
psSAR10g [W/Kg]	0.537	0.547
Power Drift [dB]	-0.02	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.6
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S82US, BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

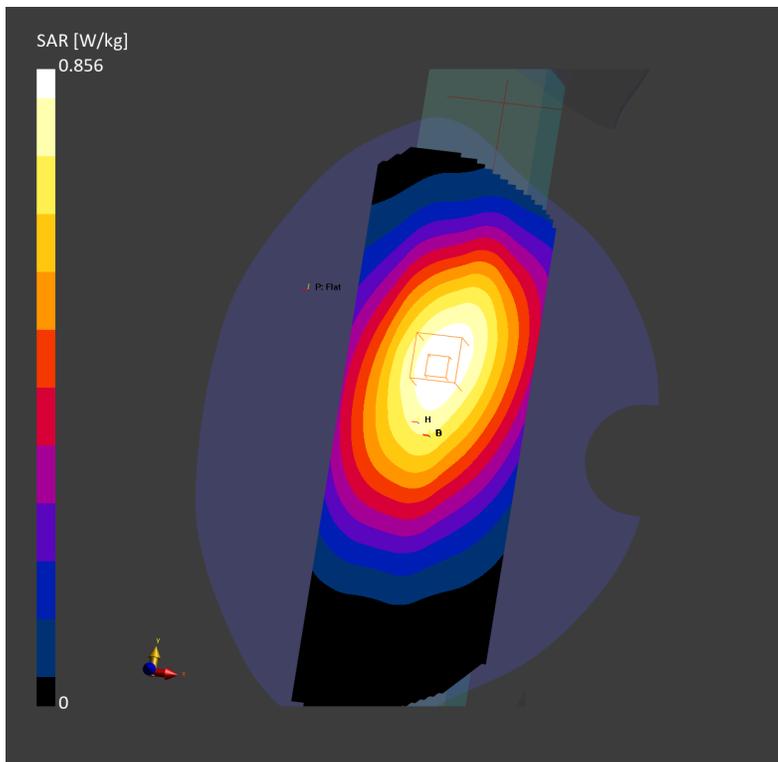
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 10:31	2025-06-02, 10:44
psSAR1g [W/Kg]	0.808	0.206
psSAR10g [W/Kg]	0.587	0.075
Power Drift [dB]	-0.03	N/A
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.1
Dist 3dB Peak [mm]		2.4



Battery - Head

Head SAR					
Battery		Output Power (W)	Freq	Body SAR 1g(W/Kg)	Body SAR 10g(W/Kg)
BP-283	2010mAh	5.3	470	4.100	3.030
BP-284	3210mAh	5.3	470	4.490	3.320
BP-303	3350mAh	5.3	470	1.230	0.894
BP-305	5xAA	5.3	470	0.853	0.631

Measurement Report for IC-F4400DT – S82US, FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

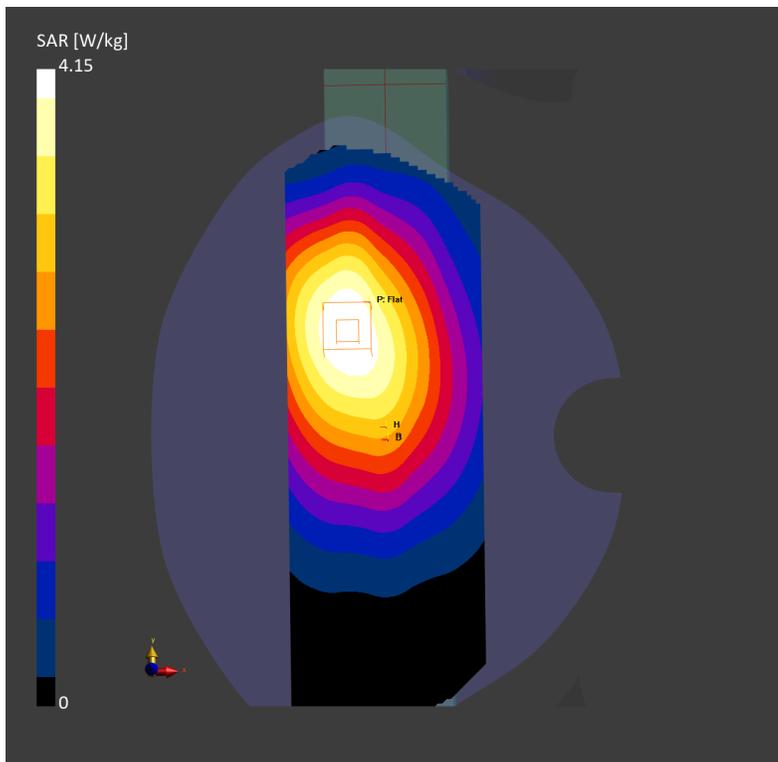
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 10:07	2025-06-02, 10:13
psSAR1g [W/Kg]	3.93	4.10
psSAR10g [W/Kg]	2.87	3.03
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – BP284 S82US, FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – BP284 S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

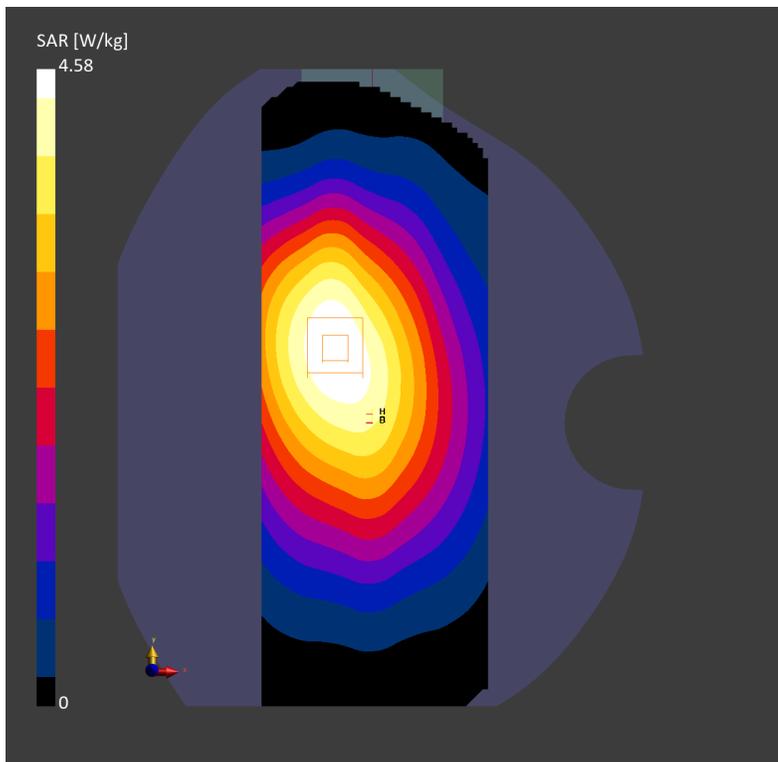
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Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30, 11:34	2025-05-30, 11:41
psSAR1g [W/Kg]	4.34	4.49
psSAR10g [W/Kg]	3.16	3.32
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.6
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – BP303 S82US, FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – BP303 S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

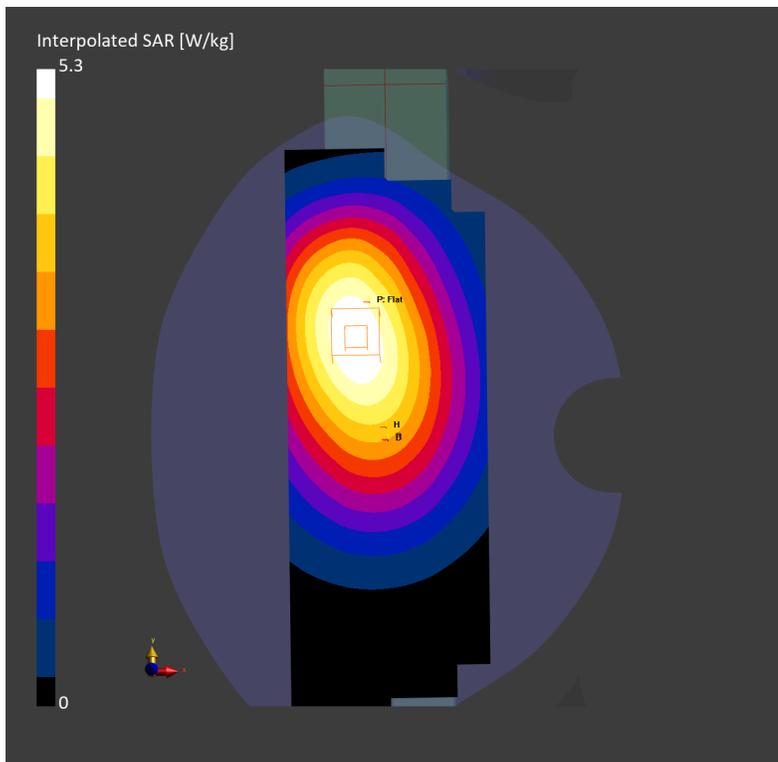
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Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-30, 13:59	2025-05-30, 14:05
psSAR1g [W/Kg]	1.21	1.23
psSAR10g [W/Kg]	0.876	0.894
Power Drift [dB]	-0.07	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S82US, FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

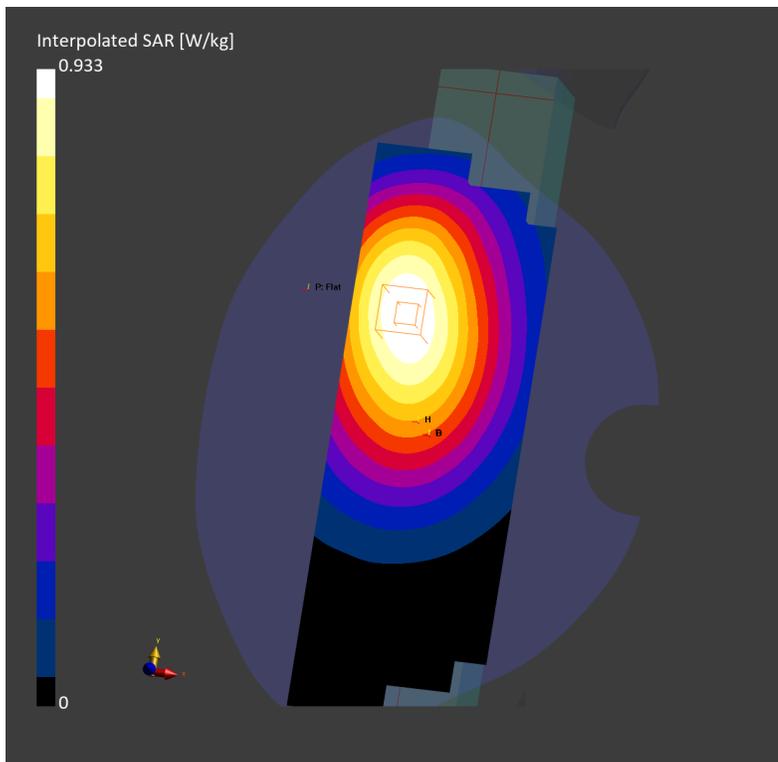
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 10:51	2025-06-02, 10:57
psSAR1g [W/Kg]	0.834	0.853
psSAR10g [W/Kg]	0.609	0.631
Power Drift [dB]	-0.03	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.3
Dist 3dB Peak [mm]		> 15.0



Belt clip- Body

Body SAR 50% duty cycle				
Belt Clip	Output Power (W)	Freq	Body SAR 1g(W/Kg)	Body SAR 10g(W/Kg)
			BP-284	BP-284
			3210mAh	3210mAh
MB-136	5.3	470	3.488	2.573
MB-133	5.3	470	2.455	1.847

Head SAR

Measurement Report for IC-F4400DT – S76UC, FRONT, D450, CW, Channel 25 (425.000

MHz) Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	425.000, 25	10.65	0.799	42.8

Hardware Setup

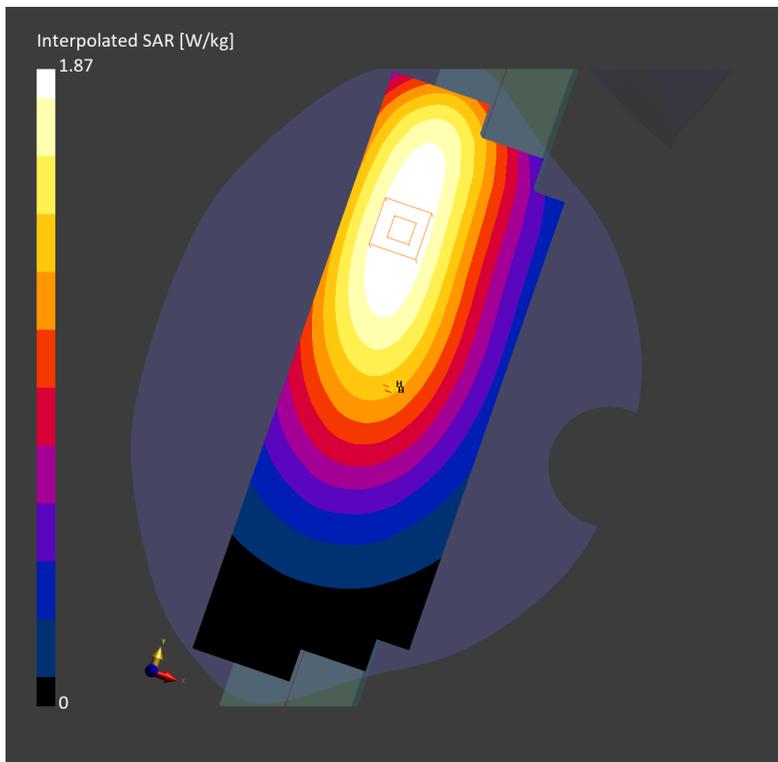
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-06-03	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03, 09:17	2025-06-03, 09:23
psSAR1g [W/Kg]	1.68	1.72
psSAR10g [W/Kg]	1.23	1.29
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S76UC, FRONT, D450, CW, Channel 70 (470.000

MHz) Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

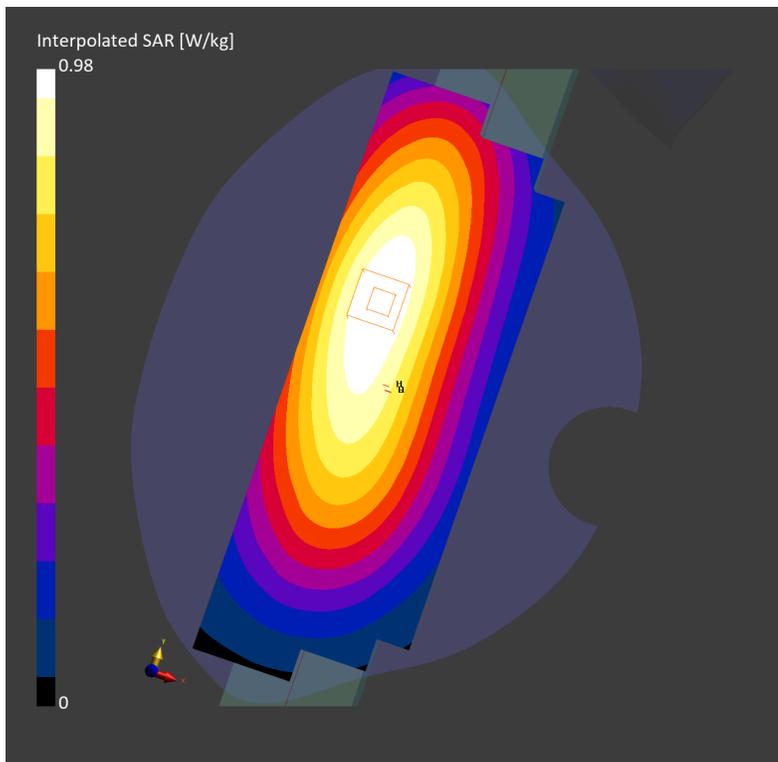
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Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 17:19	2025-06-02, 17:25
psSAR1g [W/Kg]	0.877	0.914
psSAR10g [W/Kg]	0.641	0.677
Power Drift [dB]	-0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.9
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S81U, FRONT, D450, CW, Channel 25 (425.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	425.000, 25	10.65	0.799	42.8

Hardware Setup

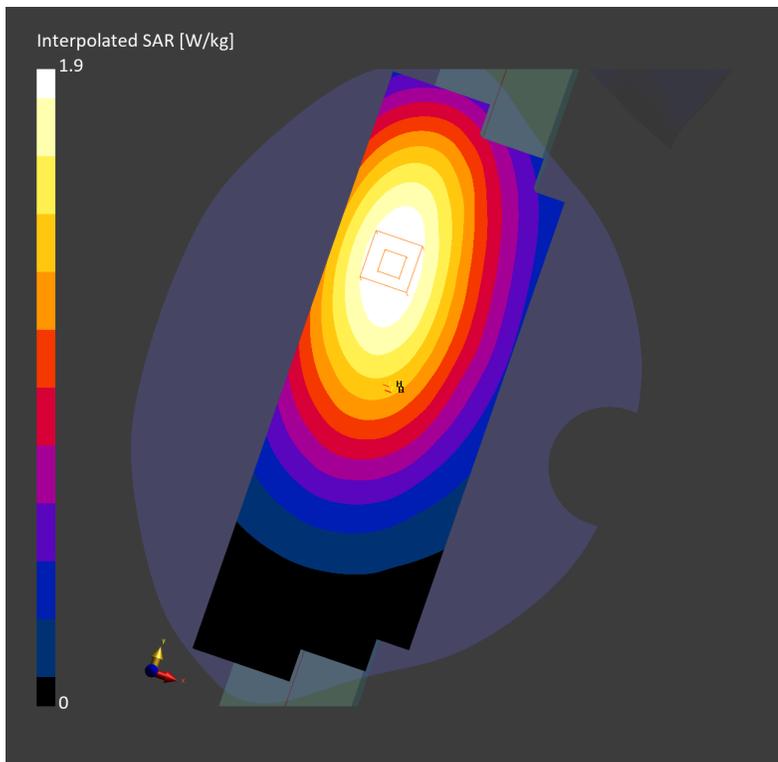
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-06-03	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03, 09:03	2025-06-03, 09:10
psSAR1g [W/Kg]	1.71	1.14
psSAR10g [W/Kg]	1.26	0.855
Power Drift [dB]	-0.26	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S81US, FRONTD450CW,Channel 25,425.000

MHz) Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	425.000, 25	10.65	0.799	42.8

Hardware Setup

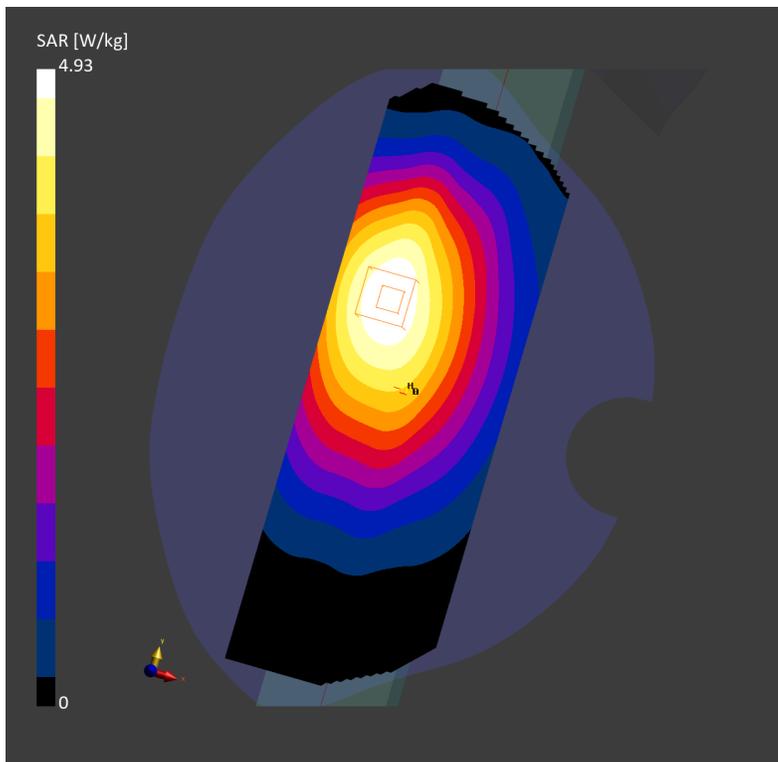
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-06-03	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03, 16:13	2025-06-03, 16:19
psSAR1g [W/Kg]	4.47	4.01
psSAR10g [W/Kg]	3.19	2.60
Power Drift [dB]	-0.27	-1.62
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.0
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S82U, FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

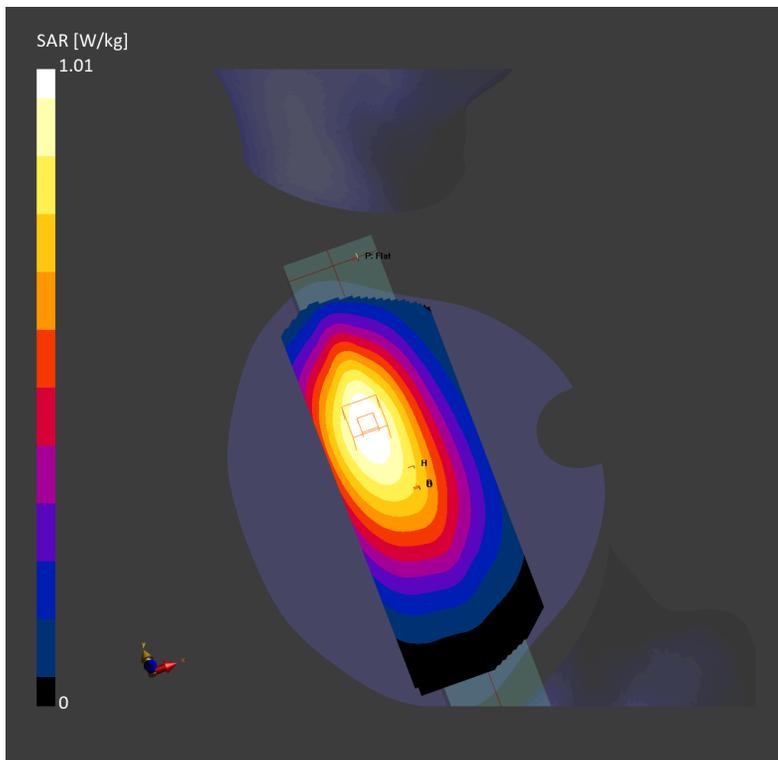
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 16:52	2025-06-02, 17:00
psSAR1g [W/Kg]	2.73	2.85
psSAR10g [W/Kg]	1.99	2.11
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.0
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S82US, FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

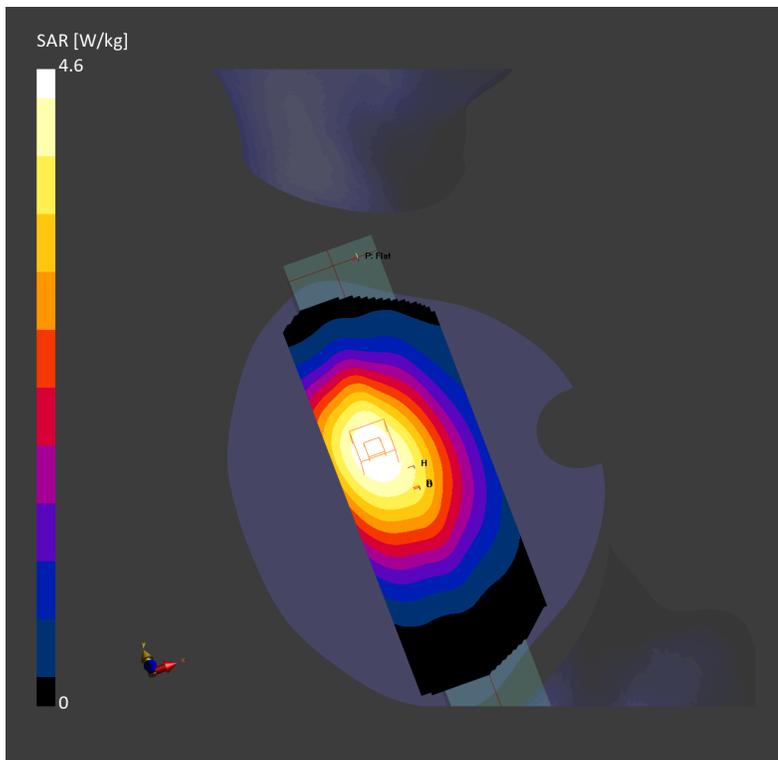
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 16:38	2025-06-02, 16:46
psSAR1g [W/Kg]	4.35	4.21
psSAR10g [W/Kg]	3.17	2.65
Power Drift [dB]	0.01	-1.89
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.5
Dist 3dB Peak [mm]		10.8



Measurement Report for IC-F4400DT – S83U , FRONT, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	470.000, 70	10.65	0.839	41.6

Hardware Setup

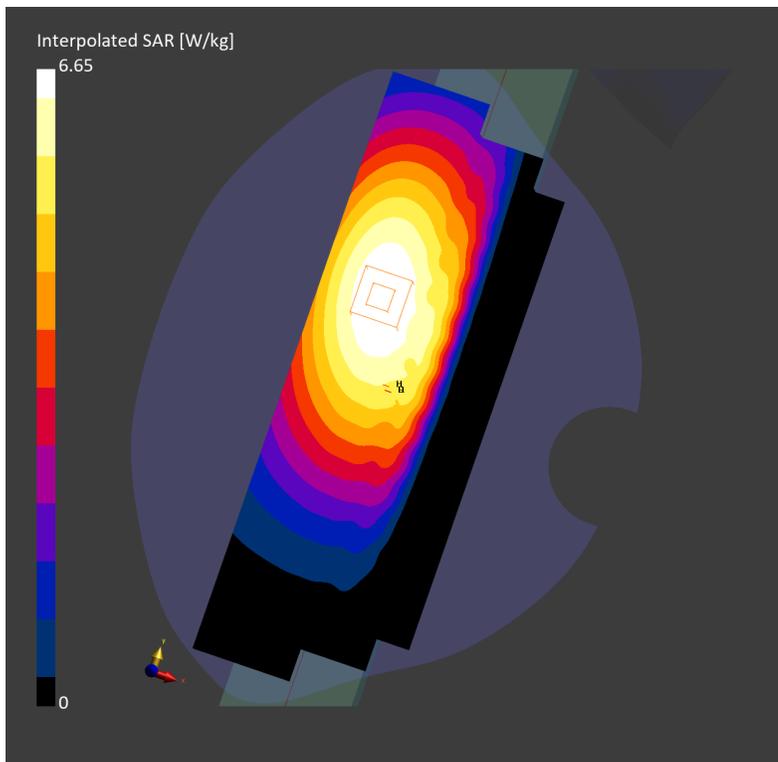
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-06-03	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-03, 08:28	2025-06-03, 08:34
psSAR1g [W/Kg]	5.95	6.12
psSAR10g [W/Kg]	4.36	4.55
Power Drift [dB]	N/A	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – FA-S76UC BACK, D450 CW, Channel 25 (425.000MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	425.000, 25	10.65	0.843	45.1

Hardware Setup

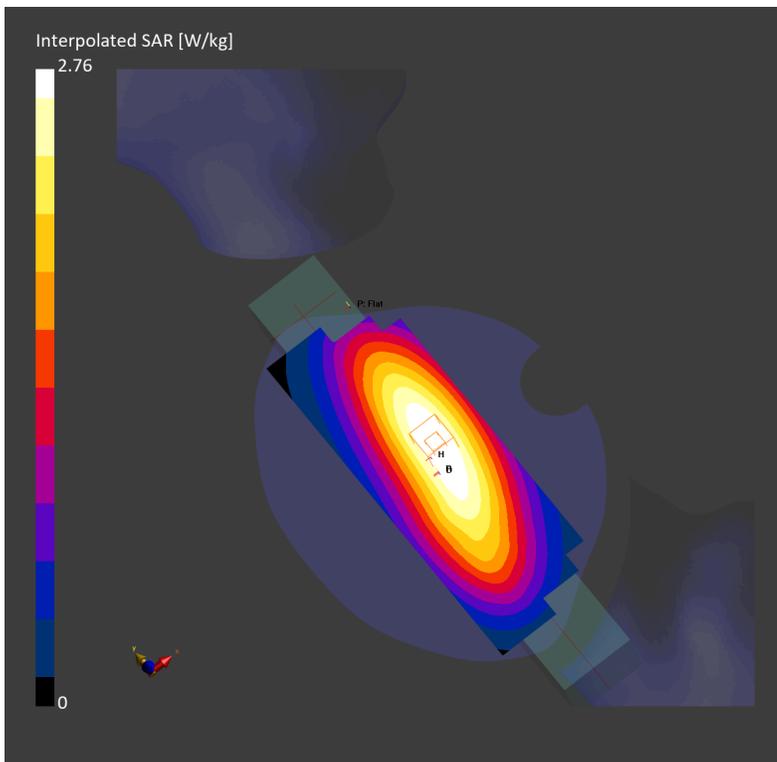
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 16:09	2025-06-02, 16:15
psSAR1g [W/Kg]	2.47	2.58
psSAR10g [W/Kg]	1.81	1.90
Power Drift [dB]	0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.6
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S76UC, BACK, D450, CW, Channel 70 (470.000

MHz) Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

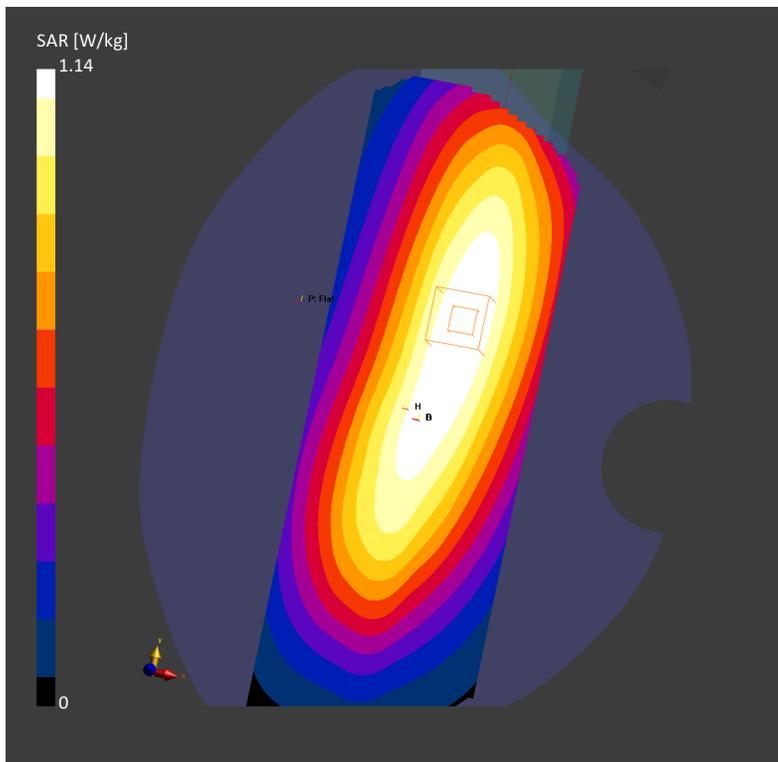
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 14:46	2025-06-02, 15:01
psSAR1g [W/Kg]	1.09	1.12
psSAR10g [W/Kg]	0.792	0.822
Power Drift [dB]	0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S82US, BACK, D450, CW, Channel 25 (425.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – S82US, ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	425.000, 25	10.65	0.843	45.1

Hardware Setup

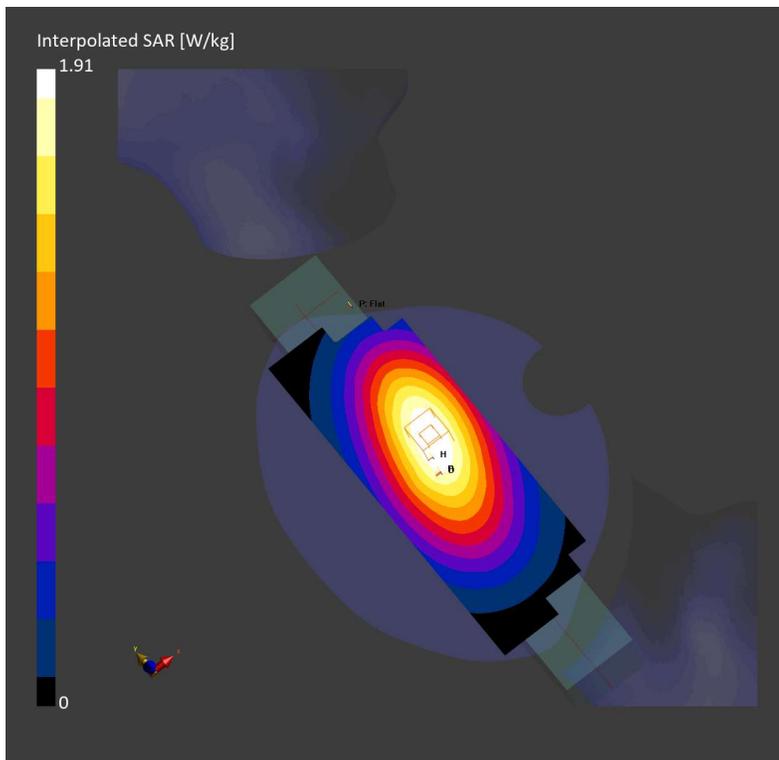
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 15:46	2025-06-02, 16:02
psSAR1g [W/Kg]	1.71	2.61
psSAR10g [W/Kg]	1.25	1.78
Power Drift [dB]	-0.01	N/A
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.8
Dist 3dB Peak [mm]		24.5



Measurement Report for IC-F4400DT – S81 U, BACK, D450, CW, Channel 25 (425.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	425.000, 25	10.65	0.843	45.1

Hardware Setup

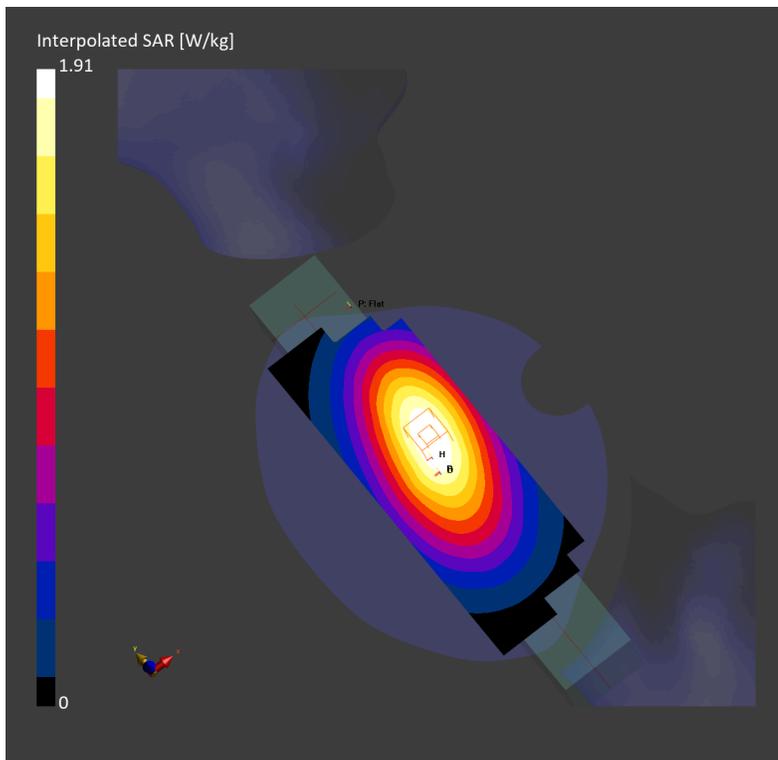
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 15:46	2025-06-02, 16:02
psSAR1g [W/Kg]	1.71	2.61
psSAR10g [W/Kg]	1.25	1.78
Power Drift [dB]	-0.01	N/A
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.8
Dist 3dB Peak [mm]		24.5



Measurement Report for IC-F4400DT – S82U BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

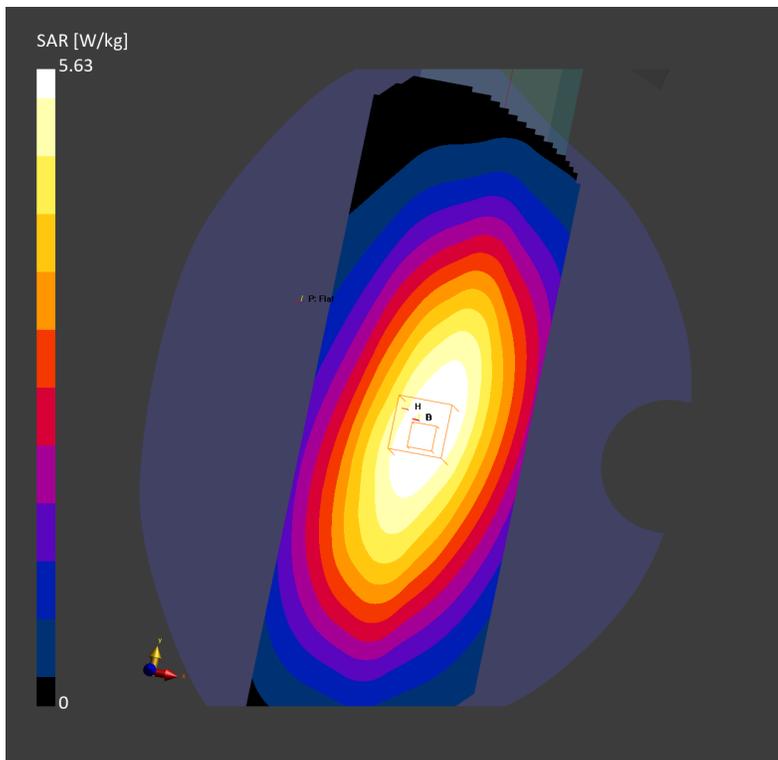
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 14:21	2025-06-02, 14:27
psSAR1g [W/Kg]	3.50	3.59
psSAR10g [W/Kg]	2.54	2.64
Power Drift [dB]	0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S82US, BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

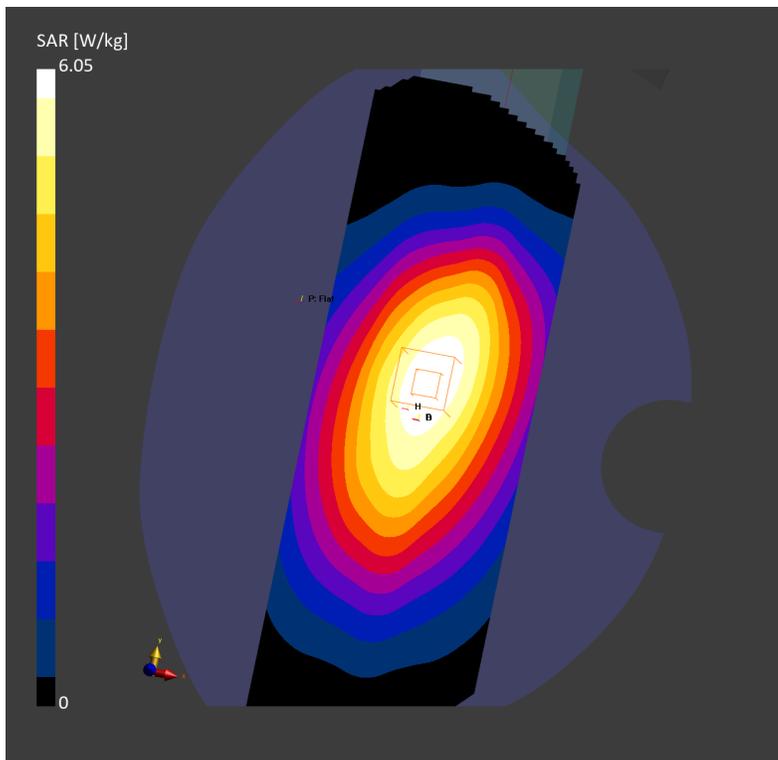
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 14:08	2025-06-02, 14:14
psSAR1g [W/Kg]	5.72	5.89
psSAR10g [W/Kg]	4.14	4.30
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.9
Dist 3dB Peak [mm]		> 15.0



Measurement Report for IC-F4400DT – S83U, BACK, D450, CW, Channel 70 (470.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
IC-F4400DT – ICOM	360.0 x 55.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	470.000, 70	10.65	0.884	43.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-04-24	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-02, 15:07	2025-06-02, 15:13
psSAR1g [W/Kg]	6.00	6.10
psSAR10g [W/Kg]	4.36	4.49
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.1
Dist 3dB Peak [mm]		> 15.0

